# A 10-bit Segmented CMOS DAC

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### Overview

- "The world we live in is analog." 1
- All data processing happens digitally.
- Interfaces are needed to convert between analog and digital domains.
- We will focus on Digital-to-Analog Converters (DACs).

<sup>&</sup>lt;sup>1</sup>Source: Peter Kinget, https://www.ee.columbia.edu/~kinget/WhyAnalog/circuitcellar\_The\_World\_Is\_Analog\_201410.pdf

└─ Introduction └─ Background

## Background

- A DAC converts a digital input to an analog output.
- Many different topologies of DAC are available; we will look at current-steering DACs.
- Current-steering DACs are the superior choice out of all topologies for high-frequency applications and driving resistive loads without needing buffers.

— Background

### Ideal DAC

■ The increase in output current is the same for every LSB increase in the digital code.

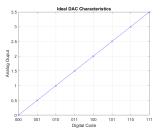


Figure 1: Ideal DAC Characteristics

 As input increases, the output always increases. Hence it is monotonic. Background

### Realistic DACs

- As we increment the digital code by 1 LSB, the change in the output current may not always be equal.
- Further, the output might fall from its previous value as input is incremented. That is, the DAC might be non-monotonic.

☐Introduction

## Examples of Realistic DACs

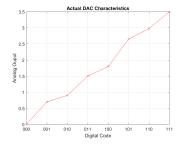


Figure 2: Example of a monotonic non-ideal DAC

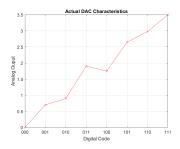


Figure 3: Example of a non-monotonic non-ideal DAC

#### Static Errors

### Definition (Integral Non-Linearity (INL))

The difference between the actual and ideal analog output values for a particular digital code.<sup>2</sup>

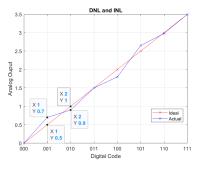
### Definition (Differential Non-Linearity (DNL))

The deviation in analog output step sizes away from 1 LSB.<sup>2</sup>

<sup>&</sup>lt;sup>2</sup>Source: Carusone, Tony Chan, David Johns, Kenneth W. Martin, and David Johns. Analog Integrated Circuit Design.

# Example

• For the example given below, 1 LSB = 0.5



- INL for 001 is (0.7 0.5)/0.5 = 0.4 LSB
- DNL for the segment considered is ((0.9 0.7)/0.5) 1 = -0.6 LSB

### Problem Statement

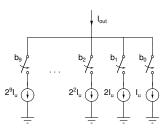
We want to design a 10-bit current-steering DAC with:

- INL<sub>max</sub> = 1 LSB
- $DNL_{max} = 0.5 LSB$
- Optimal chip area and digital complexity

## Binary-Weighted DAC

- Each digital bit controls a switch carrying a current of a different binary weight.
- If the unit cell carries current  $I_u$ , and if the bits are labeled  $b_0$  to  $b_9$ , with  $b_0$  representing the LSB, the output is

$$I_{out} = b_9(2^9 I_u) + b_8(2^8 I_u) + \ldots + b_0(I_u)$$
 (1)



## Advantages

- Digital bits directly control the switches; there is no need for decoding logic.
- Complexity is relatively low.

## Disadvantages

- In reality, all the current sources are not perfectly matched. Each current source has a random variation, and hence the current through each unit cell is  $I + \Delta I_u$ .
- All switches toggle at the same time at the mid-code transition (01 1111 1111  $\rightarrow$  10 0000 0000) leading to a glitch.
- The current before the transition is  $(2^{N-1}-1)(I+\Delta I_u)$ , and after would be  $2^N(I+\Delta I_u)$ . Mismatches might even cause the output to be non-monotonic.

### Disadvantages

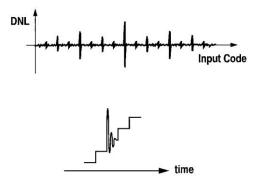
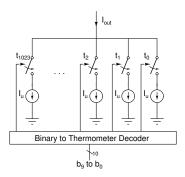


Figure 4: Example of a glitch <sup>3</sup>

 $<sup>^3</sup>$ Source: Chi-Hung Lin and K. Bult, "A 10-b, 500-MSample/s CMOS DAC in 0.6 mm $^2$ ," in IEEE Journal of Solid-State Circuits

### Thermometer-Coded DAC

- $(2^{10} 1)$  unit current sources are used in place of the 10 binary-weighted current sources.
- Only one new current source is switched on when the digital input is incremented by 1 LSB.



## Advantages

- Mid-code transition no longer causes a significant glitch since just one new current source switches on.
- The glitch amplitude is directly proportional to the change in digital code since exactly those many unit cells switch, in contrast to the unpredictable glitch amplitude in the previous architecture.
- DNL error of a thermometer-coded DAC is much lower than that of a binary-weighted DAC.

### Disadvantages

- An additional binary-to-thermometer decoder is needed.
- Each of the 1023 unit cells needs a decoder to determine whether they turn on or not, depending on the thermometer bit input.
- Therefore, digital complexity is very high.

Need for Segmentation

## Need for Segmentation

We want to leverage the benefits of both architectures:

- The high accuracy of thermometer-coded DACs
- The low digital complexity of binary-weighted DACs

For simplicity, a fully binary-weighted DAC is regarded as 0% segmented and a thermometer-coded DAC as 100% segmented.

Need for Segmentation

### Maximum INL and DNL errors

■ The expression for maximum INL of a DAC (regardless of % segmentation), for a random change of  $\sigma$  in the current  $I_u$ , is given by <sup>4</sup>

$$INL_{max} = \frac{\sigma}{2I_u} \sqrt{2^N}$$
 (2)

■ For  $B_b$  binary bits and  $B_t = N - B_b$  thermometer bits, the maximum DNL is approximately

$$DNL_{max} = \frac{\sigma}{2I_{II}} \sqrt{2^{B_b + 1}} \tag{3}$$

<sup>&</sup>lt;sup>4</sup>Source: B. Razavi, "The Current-Steering DAC [A Circuit for All Seasons]," in IEEE Solid-State Circuits Magazine

□ Need for Segmentation

# Varying % segmentation

Table 1: Trade-Offs With Variation in % Segmentation

Architecture	INL	DNL	No. of decoding units
Fully Binary	$16\sigma$	$32\sigma$	0
Segmented ( $B_t = 2$ )	$16\sigma$	$22.63\sigma$	3
Segmented $(B_t = 5)$	$16\sigma$	$8\sigma$	31
Segmented $(B_t = 8)$	$16\sigma$	$2.83\sigma$	255
Fully Thermometer	$16\sigma$	σ	1023

## Area Requirements

- Let  $\sigma = 0.5$  LSB represent the DNL<sub>max</sub>.
- lacktriangle The dependence of area on  $\sigma$  is given by  $^5$

Area 
$$\propto \frac{1}{\sigma^2}$$
 (4)

<sup>&</sup>lt;sup>5</sup>Source: M. J. M. Pelgrom, A. C. J. Duinmaijer and A. P. G. Welbers, "Matching properties of MOS transistors," in IEEE Journal of Solid-State Circuits

—Segmented DAC └─Area Requirements

## Area Requirements

Let  $A_{\rm unit}$  represents the minimum analog area of a thermometer-coded architecture to have a DNL<sub>max</sub> =  $\sigma$ 

Table 2: Area and Static Error Conditions for Binary-Weighted and Thermometer-Coded DAC

Specification	Binary-Weighted	Thermometer-Coded
DNL	$32\sigma$	$\sigma$
INL	$16\sigma$	$16\sigma$
Area for DNL = $0.5 LSB$	1024A <sub>unit</sub>	$A_{unit}$
Area for INL = 1 LSB	64A <sub>unit</sub>	64A <sub>unit</sub>

# **Optimal Segmentation**

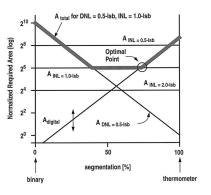


Figure 5: Normalized chip area versus percentage segmentation <sup>6</sup>

<sup>&</sup>lt;sup>6</sup>Source: Chi-Hung Lin and K. Bult, "A 10-b, 500-MSample/s CMOS DAC in 0.6 mm<sup>2</sup>," in IEEE Journal of Solid-State Circuits

Optimal Segmentation

# **Optimal Segmentation**

- All points on the highlighted portion of the horizontal line would meet the maximum INL and DNL targets in the same area.
- Using the maximal segmentation possible would result in the least DNL error and give the best total harmonic distortion performance, and hence is considered the optimal point.
- The optimal point corresponds to 8 thermometer bits and 2 binary bits for the specifications we considered.

#### Conclusion

- Thermometer-coded DACs have fewer spurious frequency components compared to binary-weighted DACs owing to smaller glitches.
- Digital complexity can be reduced by choosing an optimal percentage of segmentation while meeting the INL and DNL specifications and maintaining the minimum possible area.

### References

- Chi-Hung Lin and K. Bult, "A 10-b, 500-MSample/s CMOS DAC in 0.6 mm<sup>2</sup>," in IEEE Journal of Solid-State Circuits, vol. 33, no. 12, pp. 1948-1958, Dec. 1998, doi: 10.1109/4.735535.
- B. Razavi, "The Current-Steering DAC [A Circuit for All Seasons]," in IEEE Solid-State Circuits Magazine, vol. 10, no. 1, pp. 11-15, Winter 2018, doi: 10.1109/MSSC.2017.2771102.
- M. J. M. Pelgrom, A. C. J. Duinmaijer and A. P. G. Welbers, "Matching properties of MOS transistors," in IEEE Journal of Solid-State Circuits, vol. 24, no. 5, pp. 1433-1439, Oct. 1989, doi: 10.1109/JSSC.1989.572629.
- Carusone, Tony Chan, David Johns, Kenneth W. Martin, and David Johns. Analog Integrated Circuit Design. Hoboken, NJ: John Wiley & Sons, 2012.